Silicon N-channel IGBT 3300V F version

FEATURES

* Soft switching behavior, low switching loss & low conduction loss :

Soft low-injection punch-through

Advanced Trench High conductivity IGBT.

- * Low driving power due to low input capacitance with trench MOS gate.
- * Low noise recovery: Ultra soft fast recovery diode.
- * High Current rate Package.
- * Low R_{th(j-c)} & low stray inductance.
- * RoHS
- * High thermal fatigue durability: (delta Tc=70K, N>30,000cycles)

ABSOLUTE MAXIMUM RATINGS (T_C=25°C)

Item		Symbol	Unit	MBN1800F33F
Collector Emitter Voltage		V _{CES}	V	3,300
Gate Emitter Voltage		V_{GES}	V	±20
DC DC		Ic	^	1,800
Collector Current	1ms	I _{CRM}	A	3,600
Forward Current	DC	l _F	^	1,800
Forward Current	1ms	I _{FRM}	— A	3,600
Junction Temperature	•	T _{vj op}	°C	-50 ~ +150
Storage Temperature		T _{stg}	°C	-55 ~ +150
Isolation Voltage		V _{ISO}	V _{RMS}	6,000(AC 1 minute)
Sorow Torquo	Terminals (M4/M8)	-	N·m	2/15 (1)
Screw Torque	Mounting (M6)	-	14.111	6 (2)

Notes: (1) Recommended Value 1.8±0.2/15⁺⁰-3N·m (2) Recommended Value 5.5±0.5N·m

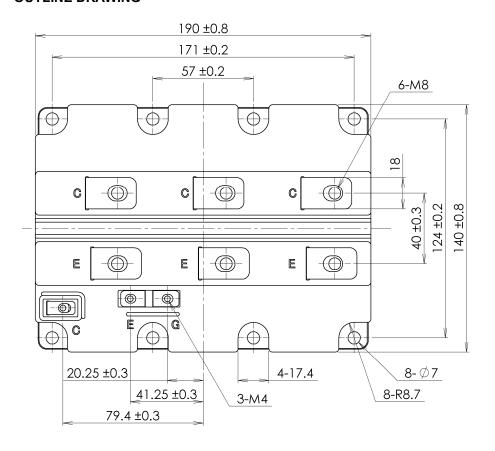
ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Тур.	Max.	Test Conditions
	1.		-	-	0.6	V _{CE} =3,300V, V _{GE} =0V, T _{vi} =25°C
Collector Emitter Cut-Off Current	ICES	mA	-	40	100	V _{CE} =3,300V, V _{GE} =0V, T _{vi} =150°C
Gate Emitter Leakage Current	I _{GES}	nA	-500	-	+500	V _{GE} =±20V, V _{CE} =0V, T _{vi} =25°C
Collector Emitter Saturation Voltage	V _{CEsat}	V	2.5	2.85	3.5	I _C =1,800A, V _{GE} =15V, T _{vi} =150°C
Gate Emitter Threshold Voltage	V _{GE(th)}	V	5.5	6.5	7.5	V _{CE} =10V, I _C =1,800mA, T _{vi} =25°C
Input Capacitance	Cies	nF	-	132	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C
Internal Gate Resistance	R _{G(int)}	Ω	-	1.3	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C
Turn On Delay Time	t _{d(on)}		-	0.8	-	V _{CC} =1,800V, I _C =1,800A
Rise Time	t _r	μS	-	0.3		L _S =80nH
Turn Off Delay Time	t _{d(off)}		-	2.2	-	$R_G(\text{on/off})=4.7\Omega/5.6\Omega$ (3)
Fall Time	t _f		-	1.8	-	$V_{GE}=\pm 15V, T_{vj}=150^{\circ}C$
Forward Voltage Drop	V _F	V	2.2	2.6	2.9	I _F =1,800A, V _{GE} =0V, T _{vj} =150°C
Reverse Recovery Time	t _{rr}	μS	-	0.7	-	V _{CC} =1,800V, I _F =1,800A, L _S =80nH T _{vi} =150°C
Turn On Loss	Eon	J/P	-	3.7	-	V _{CC} =1,800V, I _C =1,800A, L _S =80nH
Turn Off Loss	E _{off}	J/P	-	3.3	-	$R_G(\text{on/off})=4.7\Omega/5.6\Omega$ (3)
Reverse Recovery Loss	Err	J/P	-	2.4	-	$V_{GE}=\pm 15V, T_{vj}=150^{\circ}C$
Short Circuit Pulse Width	t _{sc}		10			V _{CC} =2,000V, Ls=80nH
Short Circuit Fuise Width	Lsc	μS	10	-	_	$R_G(on/off)=4.7/56\Omega, V_{GE}=\pm 15V, T_{vj}=150^{\circ}C$
Stray inductance module	L _{SCE}	nΗ	-	7	-	
Thermal Impedance IGBT	R _{th(j-c)}	K/W	-	-	0.0067	Junction to case
FWD	R _{th(j-c)}		-	-	0.012	Junion to case
Contact Thermal Impedance	R _{th(c-f)}	K/W	-	0.005	-	Case to fin

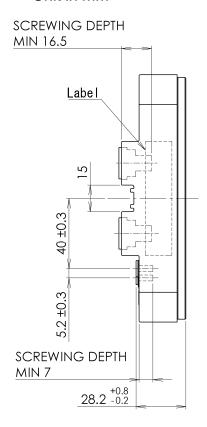
Notes: (3) R_G value is a test condition value for evaluation, not recommended value. Please, determine the suitable R_G value by measuring switching behaviors.

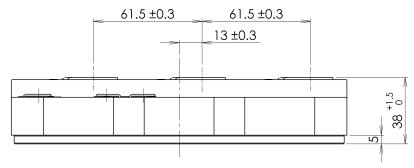
- * Please contact our representatives at order.
- * For improvement, specifications are subject to change without notice.
- * For actual application, please confirm this spec sheet is the newest revision.
- * ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.

OUTLINE DRAWING



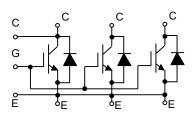
Unit in mm

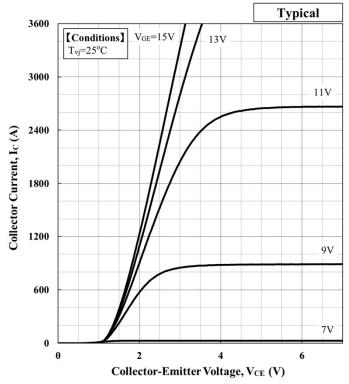




Weight: 1,300g

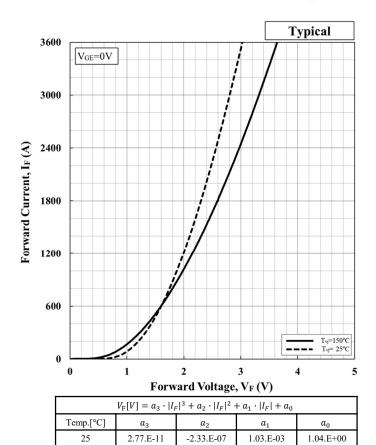
CIRCUIT DIAGRAM





$V_{\text{CE}}(sat)[V] = a_3 \cdot I_c ^3 + a_2 \cdot I_c ^2 + a_1 \cdot I_c + a_0$								
Temp.[°C]	Temp.[°C] $V_{GE}[V]$ a_3 a_2 a_1 a_0							
25	15	1.58.E-11	-1.20.E-07	7.57.E-04	1.23.E+00			

Collector Current vs. Collector Emitter Voltage



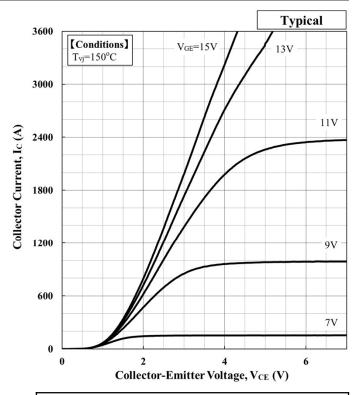
-2.93.E-07 Forward Voltage of free-wheeling diode

1.40.E-03

8.36.E-01

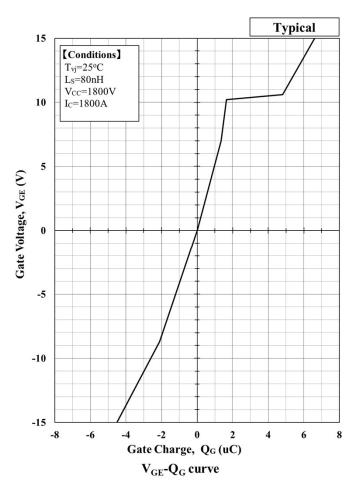
3.40.E-11

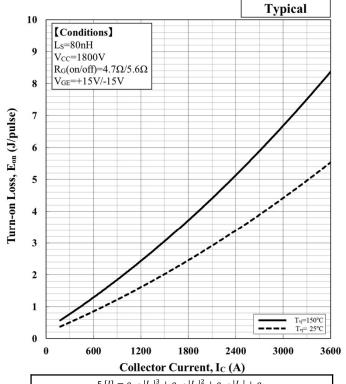
150



$V_{\text{CE}}(sat)[V] = a_3 \cdot I_c ^3 + a_2 \cdot I_c ^2 + a_1 \cdot I_c + a_0$							
Temp.[°C] $V_{GE}[V]$ a_3 a_2 a_1 a_0							
150	15	3.35.E-11	-2.27.E-07	1.28.E-03	1.09.E+00		

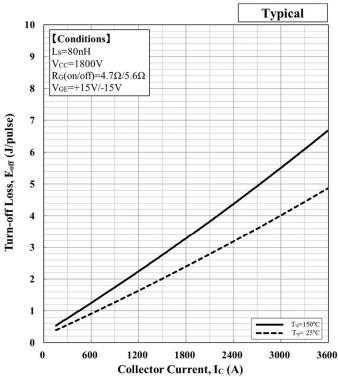
Collector Current vs. Collector Emitter Voltage





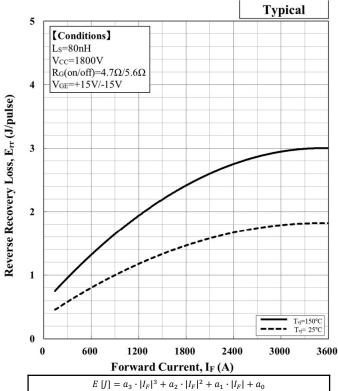
	, - ()							
	$E\left[J\right] = a_3 \cdot I_c ^3 + a_2 \cdot I_c ^2 + a_1 \cdot I_c + a_0$							
Temp.[°C] a_3 a_2 a_1 a_0								
	25	-	1.24E-07	1.04E-03	1.87E-01			
	150	-	1.88E-07	1.57E-03	2.82E-01			

Turn-on loss vs. Collector current



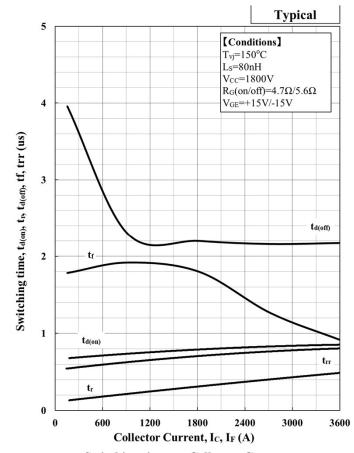
$E[J] = a_3 \cdot I_c ^3 + a_2 \cdot I_c ^2 + a_1 \cdot I_c + a_0$							
Temp.[°C] a_3 a_2 a_1 a_0							
25	-	4.68E-08	1.13E-03	2.18E-01			
150	-	6.42E-08	1.54E-03	2.99E-01			

Turn-off loss vs. Collector current

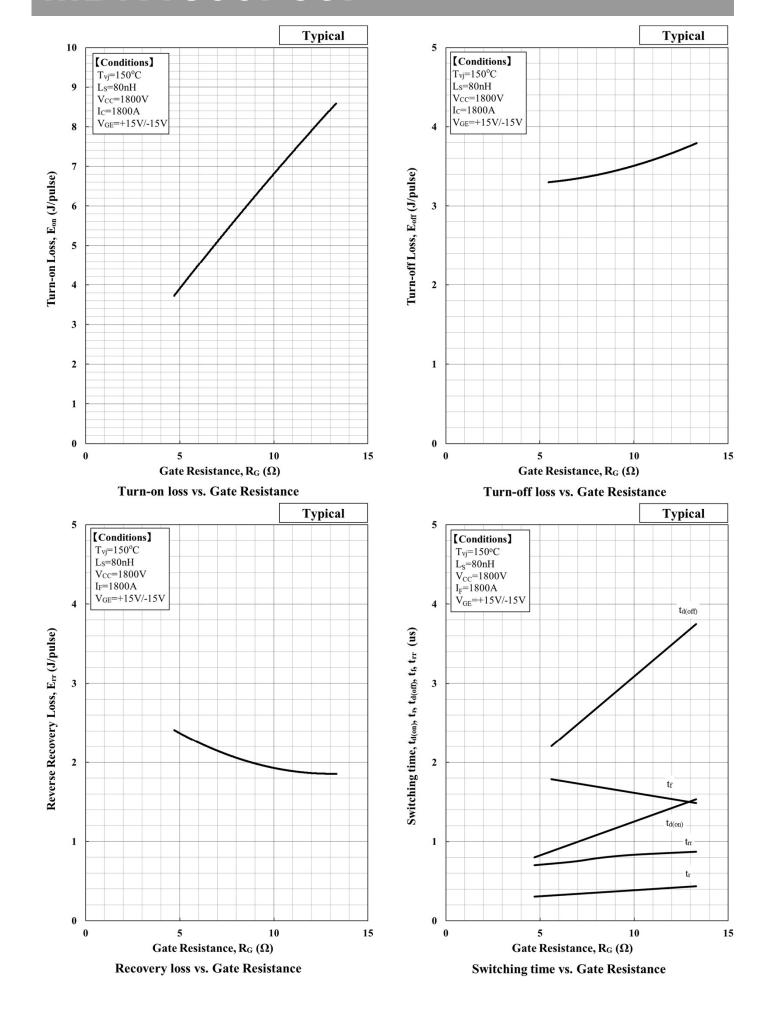


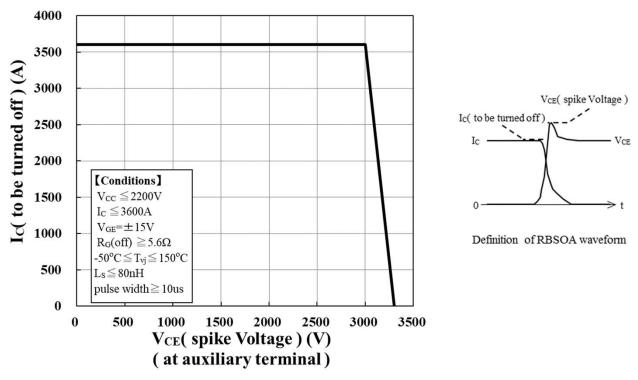
$E[J] = a_3 \cdot I_F ^3 + a_2 \cdot I_F ^2 + a_1 \cdot I_F + a_0$							
Temp.[°C]	a_3	a_1	a_0				
25	-	-1.19E-07	8.40E-04	3.39E-01			
150	-	-1.96E-07	1.38E-03	5.58E-01			

Recovery loss vs. Forward current

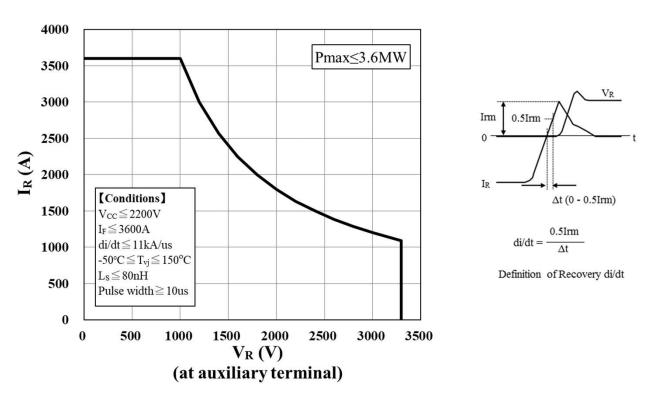


Switching time vs. Collector Current

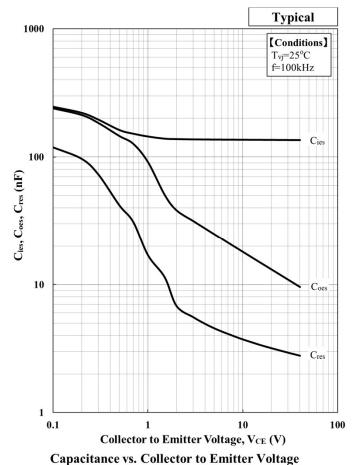




Reverse Bias Safe Operation Area (RBSOA)



Reverse Recovery Safe Operation Area (RRSOA)



0.1 Diode

Diode

O.001

O.0001

O.0001

O.0001

O.001

O.

Transient Thermal Impedance Curve

Foster model lumped circuit constant

n	1	2	3	4	Unit
R th, IGBT [n]	4.32E-03	1.45E-03	8.73E-04	5.10E-05	[K/W]
C th, IGBT [n]	2.93E+01	1.07E+01	3.14E+00	6.21E+00	[J/K]
R th, Diode [n]	7.78E-03	2.84E-03	1.28E-03	1.00E-04	[K/W]
C th, Diode [n]	1.63E+01	5.45E+00	2.15E+00	3.16E+00	[J/K]

Cauer model lumped circuit constant

n	1	2	3	4	Unit
R th, IGBT [n]	5.84E-04	1.17E-03	1.97E-03	2.98E-03	[K/W]
C th, IGBT [n]	1.64E+00	1.09E+00	8.05E+00	2.95E+01	[J/K]
R th, Diode [n]	8.92E-04	2.14E-03	3.59E-03	5.38E-03	[K/W]
C th, Diode [n]	9.74E-01	7.11E-01	4.00E+00	1.67E+01	[J/K]

Minebea POWER SEMICONDUCTORS

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- 2. When designing an electronic circuit using semiconductor devices, please do not exceed the absolute maximum rating specified for the device under any external fluctuations. And for pulse applications, please also do not exceed the "Safe Operating Area (SOA)".
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- 7. The information given herein, including the specifications and dimensions, is subject to change without prior notice to improve product characteristics. Before ordering, purchasers are advised to contact with Minebea power semiconductor sales department for the latest version of this data sheets
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Minebea POWER SEMICONDUCTORS

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